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TEXAS INSTRUMENTS

TPD2EUSB30, TPD2EUSB30A, TPD4EUSB30

SLVSAC2F – AUGUST 2010 – REVISED OCTOBER 2015

TPDxEUSB30 2-, 4-Channel ESD Protection for Super-Speed USB 3.0 Interface

1 Features

- Supports USB 3.0 Data Rates (5 Gbps)
- IEC 61000-4-2 ESD Protection (Level 4 Contact)
- IEC 61000-4-5 Surge Protection
  - 5 A (8/20 µs)
- Low Capacitance
  - DRT: 0.7 pF (Typ)
  - DQA: 0.8 pF (Typ)
- Dynamic Resistance: 0.6 Ω (Typ)
- Space-Saving DRT, DQA Packages
- Flow-Through Pin Mapping

2 Applications

- Notebooks
- Set-Top Boxes
- DVD Players
- Media Players
- Portable Computers

3 Description

The TPD2EUSB30, TPD2EUSB30A, and TPD4EUSB30 are 2 and 4 channel Transient Voltage Suppressor (TVS) based Electrostatic Discharge (ESD) protection diode arrays. The TPDxEUSB30/A devices are rated to dissipate ESD strikes at the maximum level specified in the IEC 61000-4-2 international standard (Contact). These devices also offer 5 A (8/20 µs) peak pulse current ratings per IEC 61000-4-5 (Surge) specification.

The TPD2EUSB30A offers low 4.5-V DC break-down voltage. The low capacitance, low break-down voltage, and low dynamic resistance make the TPD2EUSB30A a superior protection device for high-speed differential IOs.

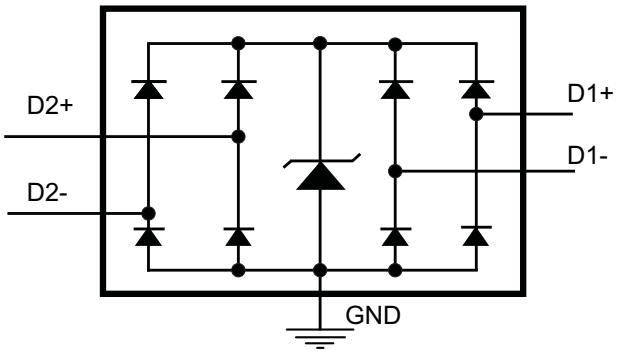
The TPD2EUSB30 and TPD2EUSB30A are offered in space saving DRT (1 mm × 1 mm) package. The TPD4EUSB30 is offered in space saving DQA (2.5 mm × 1.0 mm) package.

Device Information[1]

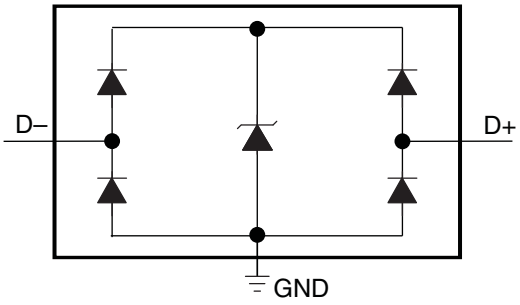
PART NUMBER	PACKAGE	BODY SIZE (NOM)
TPD2EUSB30	SOT (3)	1.00 mm x 0.80 mm
TPD2EUSB30A		
TPD4EUSB30	USON (10)	2.50 mm x 1.00 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.

TPD4EUSB30 Circuit



TPD2EUSB30/A Circuit



An IMPORTANT NOTICE at the end of this data sheet addresses availability, warranty, changes, use in safety-critical applications, intellectual property matters and other important disclaimers. PRODUCTION DATA.

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4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision E (August 2014) to Revision F — **Page**

- Moved the storage temperature to the *Absolute Maximum Ratings* table and updated the *Handling Ratings* table to an *ESD Ratings* table ... 3
- Added test condition frequency to capacitance ... 4
- Added *Community Resources* ... 13

Changes from Revision D (August 2012) to Revision E — **Page**

- Added *Handling Rating* table, *Feature Description* section, *Device Functional Modes*, *Application and Implementation* section, *Power Supply Recommendations* section, *Layout* section, *Device and Documentation Support* section, and *Mechanical, Packaging, and Orderable Information* section ... 1

Changes from Revision C (December 2011) to Revision D — **Page**

- Updated Dynamic Resistance value ... 1
- Updated Dynamic Resistance value ... 4

Changes from Revision B (July 2011) to Revision C — **Page**

- Added Insertion Loss graphic to TYPICAL OPERATING CHARACTERISTICS section. ... 6

Changes from Revision A (December 2010) to Revision B — **Page**

- Changed TOP-SIDE MARKING column in the Ordering Information Table ... 3

Changes from Original (August 2010) to Revision A — **Page**

- Added TPS2EUSB30A part to document. ... 1

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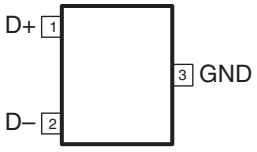
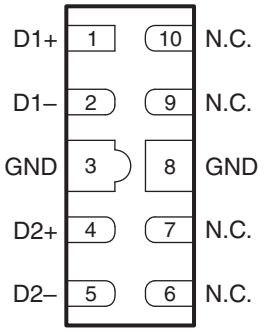
5 Pin Configuration and Functions

DRT Package
3-Pin SOT
Top View



DQA Package
10-Pin USON
Top View



Pin Functions

PIN			TYPE	DESCRIPTION
NAME	DRT	DQA		
Dx+, Dx–	1, 2	1, 2, 4, 5	ESD port	High-speed ESD clamp, provides ESD protection to the high-speed differential data lines
GND	3	3, 8	GND	Ground
N.C.	—	6, 7, 9, 10	—	Not normally connected

6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
	IO voltage (D+ and D- pins)	TPD2EUSB30, TPD4EUSB30	0	6	V
		TPD2EUSB30A	0	4	
	IEC 61000-4-5 surge current (t_p = 8/20 µs)	D+, D– pins		5	A
	IEC 61000-4-5 surge peak power (t_p = 8/20 µs)	D+, D– pins		45	W
T_A	Operating free-air temperature		–40	85	°C
T_{stg}	Storage temperature		–65	125	°C

(1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

				VALUE	UNIT
$V_{(ESD)}$	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins(1)		2500	V
		Charged device model (CDM), per JEDEC specification JESD22-C101, all pins(2)		1500	
		IEC 61000-4-2 Contact Discharge	D+, D– pins	8000	
		IEC 61000-4-2 Air-Gap Discharge (TPD2EUSB30/A)	D+, D– pins	8000	
		IEC 61000-4-2 Air-Gap Discharge (TPD4EUSB30)	D+, D– pins	9000	

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

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6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNIT
T_A operating free-air temperature		–40	85	°C
Operating Voltage	TPD2EUSB30, TPD4EUSB30	0	5.5	V
	TPD2EUSB30A	0	3.6	

6.4 Thermal Information

THERMAL METRIC[1]		TPD2EUSB30	TPD2EUSB30A	TPD4EUSB30	UNIT
		DRT (SOT)	DRT (SOT)	DQA (USON)	
		3 PINS	3 PINS	10 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	610.2	610.2	162.2	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	288.0	288.0	128.3	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	118.4	118.4	56.7	°C/W
ψ_{JT}	Junction-to-top characterization parameter	20.2	20.2	13.8	°C/W
ψ_{JB}	Junction-to-board characterization parameter	116.4	116.4	56.6	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	N/A	N/A	8.1	°C/W

(1) For more information about traditional and new thermal metrics, see the *Semiconductor and IC Package Thermal Metrics* application report, SPRA953.

6.5 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
V_{RWM}	Reverse stand-off voltage (D+ and D- pins)	TPD2EUSB30, TPD4EUSB30				5.5	V
		TPD2EUSB30A				3.6	V
V_{clamp}	Clamp voltage	D+,D– pins to ground,	I_{IO} = 1 A			8	V
I_{IO}	Current from IO port to supply pins	V_{IO} = 2.5 V,	I_D = 8 mA		0.01	0.1	µA
V_D	Diode forward voltage	D+,D– pins, lower clamp diode,	V_{IO} = 2.5 V, I_D = 8 mA	0.6	0.8	0.95	V
R_{dyn}	Dynamic resistance	D+,D– pins	I = 1 A		0.6		Ω
C_{IO-IO}	Capacitance IO to IO	D+,D– pins	V_{IO} = 2.5 V; f = 100 kHz		0.05		pF
C_{IO-GND}	Capacitance IO to GND	D+,D– pins (DRT)	V_{IO} = 2.5 V; f = 100 kHz		0.7		pF
		D1+, D1-, D2+, D2- (DQA)			0.8		
V_{BR}	Break-down voltage, TPD2EUSB30, TPD4EUSB30	I_{IO} = 1 mA		7			V
	Break-down voltage, TPD2EUSB30A	I_{IO} = 1 mA		4.5			V

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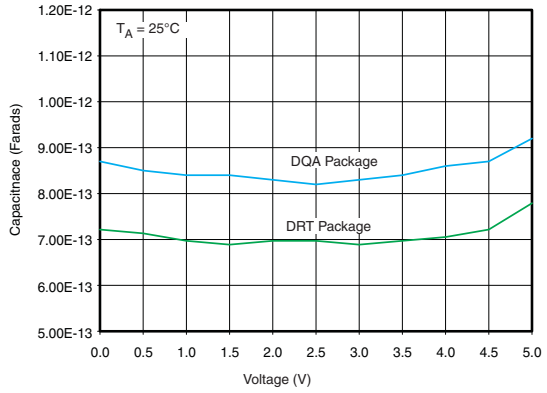
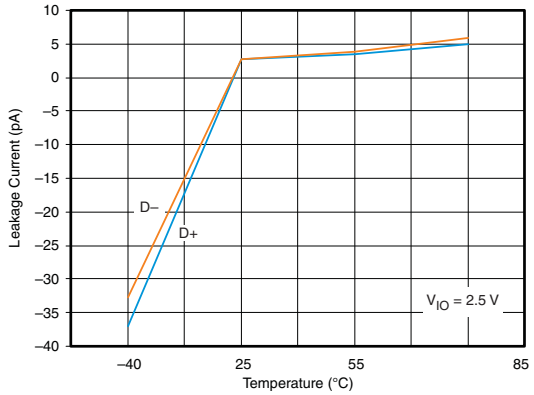
6.6 Typical Characteristics



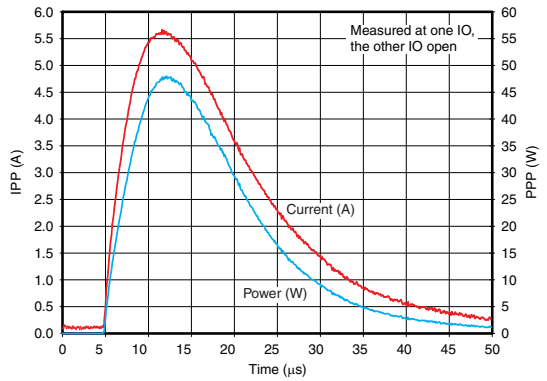
T_A = 25 °C

Figure 1. IO Capacitance vs IO Voltage



V_{IO} = 2.5 V

Figure 2. Leakage Current vs Temperature



Measured at one IO, the other IO open

Figure 3. Peak Pulse Waveforms

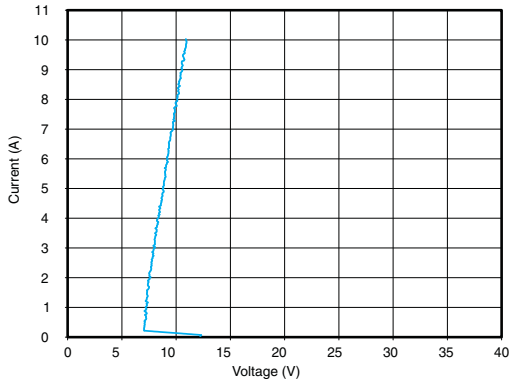


Figure 4. D+,D– Transmission Line Pulser Plot for TPD2EUSB30 (100 ns Pulse, 10 ns Rise Time)

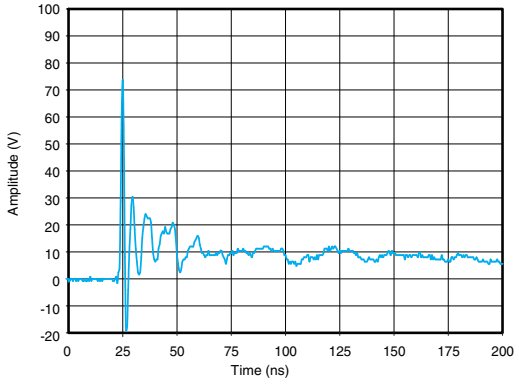


Figure 5. IEC Clamping Waveforms (8 kV Contact)

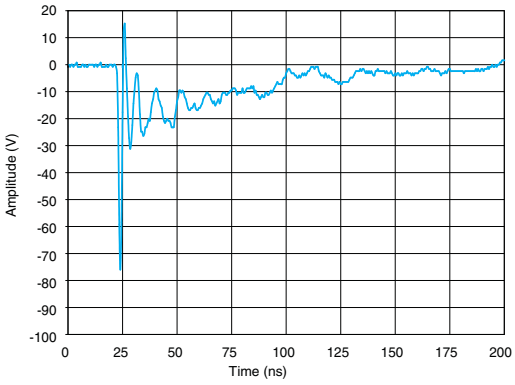


Figure 6. IEC Clamping Waveforms (–8 kV Contact)

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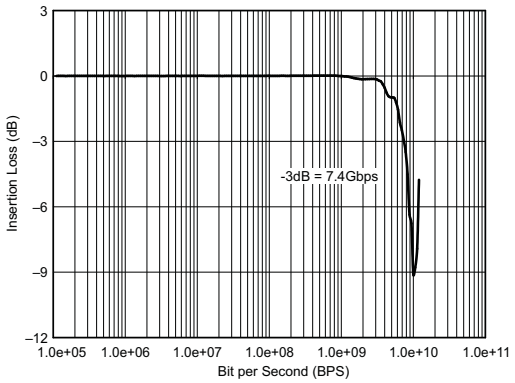
Typical Characteristics (continued)



–3 dB = 7.4 Gbps

Figure 7. Insertion Loss

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7 Detailed Description

7.1 Overview

The TPD2EUSB30, TPD2EUSB30A, and TPD4EUSB30 are 2 and 4 channel Transient Voltage Suppressor (TVS) based Electrostatic Discharge (ESD) protection diode arrays. The TPDxEUSB30/A devices are rated to dissipate ESD strikes at the maximum contact level specified in the IEC 61000-4-2 international standard (Contact). These devices also offer 5 A (8/20 µs) peak pulse current ratings per IEC 61000-4-5 (surge) specification.

7.2 Functional Block Diagrams

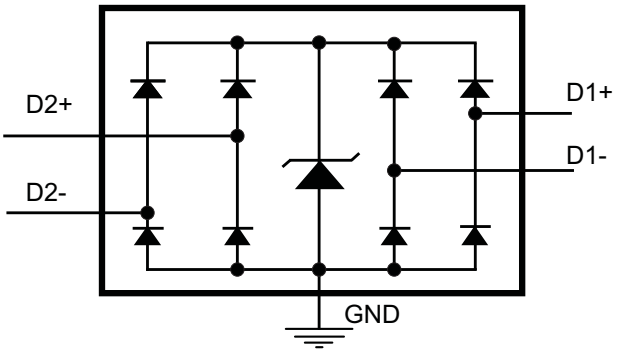

Figure 8. TPD4EUSB30 Circuit

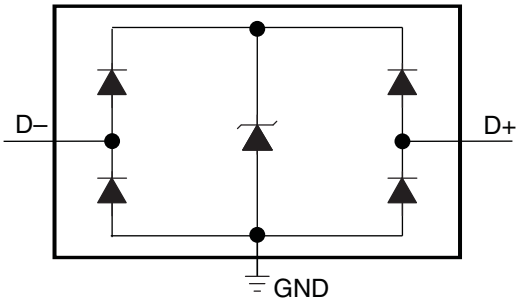

Figure 9. TPD2EUSB30/A Circuit

7.3 Feature Description

TPDxEUSB30/A is a family of uni-directional Electrostatic Discharge (ESD) protection devices with low capacitance. Each IO line is rated to dissipate ESD strikes at or above the maximum level specified in the IEC 61000-4-2 (Level 4 Contact) international standard. The TPDxEUSB30/A's low loading capacitance makes it ideal for protection super speed high-speed signals.

7.4 Device Functional Modes

The TPDxEUSB30/A family of devices are passive integrated circuits that activate whenever voltages above V_{BR} or below the lower diodes $V_{forward}$ (–0.6V) are present upon the circuit being protected. During ESD events, voltages as high as ±8 kV (contact) can be directed to ground via the internal diode network. Once the voltages on the protected lines fall below the trigger voltage of the device (usually within 10's of nano-seconds) the device reverts to passive.

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8 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

8.1 Application Information

The TPDxEUSB30/A family is a family of diode array type transient voltage suppressors (TVS) which are typically used to provide a path to ground for dissipating ESD events on hi-speed signal lines between a human interface connector and a system. As the current from ESD passes through the TVS, only a small voltage drop is present across the diode. This is the voltage presented to the protected IC. The low R_{DYN} of the triggered TVS holds this voltage, V_{CLAMP}, to a tolerable level to the protected IC.

8.2 Typical Application

This application describes a TPDxEUSB30/A eye pattern test. Figure 17 shows the lab board that was designed to demonstrate the degradation of the eye pattern quality with and without the TPD2EUSB30/A in the USB 3.0 signal path. The measurements show that there is only ~2 ps jitter penalty to the differential signal when the TPD2EUSB30/A device is added in the signal path. A similar setup was employed to measure the eye diagram for the TPD4EUSB30.

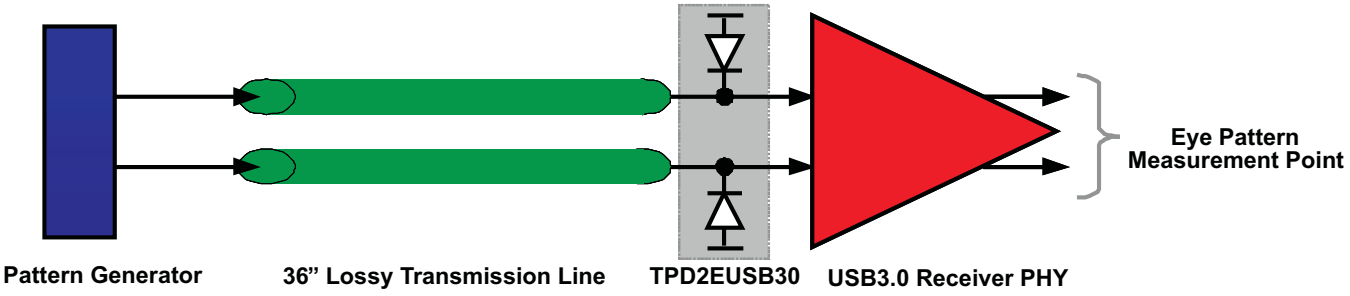

Figure 10. Measurement Setup to collect the Eye Pattern on a Reference Board with TPD2EUSB30/A

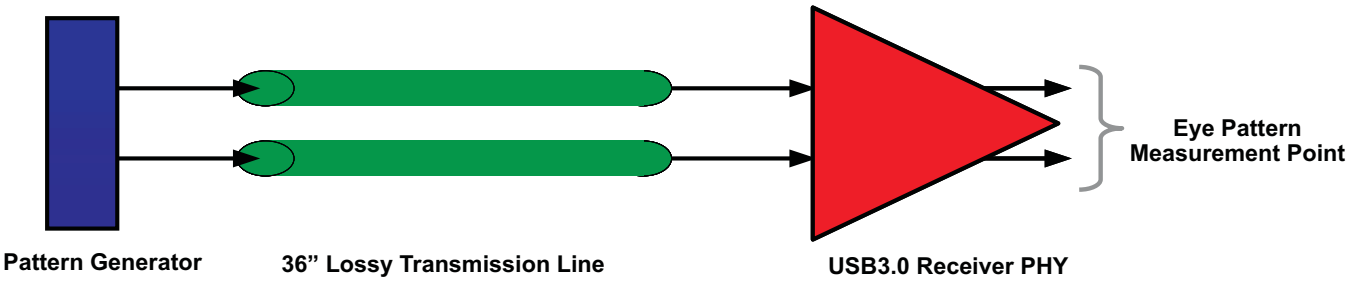

Figure 11. Measurement Setup to collect the Eye Pattern on a Reference Board with TPD2EUSB30/A

8.2.1 Design Requirements

For this design example, a single TPD2EUSB30/A is used to protect a differential data pair lines, similar to a USB 3.0 application. Given the USB application, the following parameters are known.

Table 1. Design Parameters

DESIGN PARAMETER	VALUE
Signal range on D+, and D–	0 V to 3.3 V
Operating Frequency	2.5 GHz

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8.2.2 Detailed Design Procedure

To begin the design process, some parameters must be decided upon; the designer needs to know the following:

- Signal range on all the protected lines
- Operating frequency

8.2.2.1 Signal Range on D+, D- Pins

The TPD2EUSB30 has 2 pins which support 0 to 5.5 V and the TPD2EUSB30A has 2 pins which support 0 to 3.6 V.

8.2.2.2 Operating Frequency

The 0.7 pF (TPD2EUSB30/A typ) line capacitance supports data rates in excess of 5 Gbps.

8.2.3 Application Curves

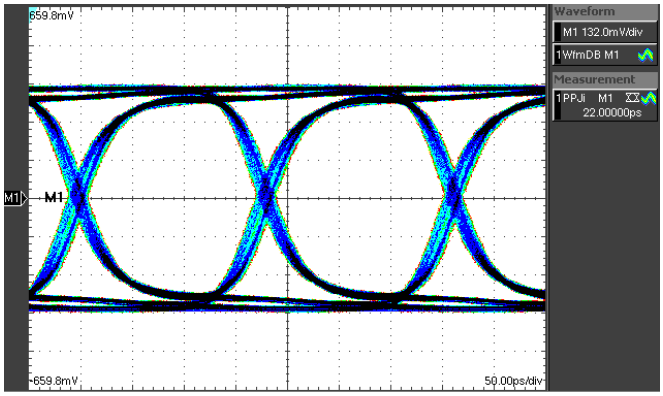

Figure 12. Output Eye Diagram Without TPD2EUSB30/A (Figure 11 Setup, 5 Gbps Data Rate)

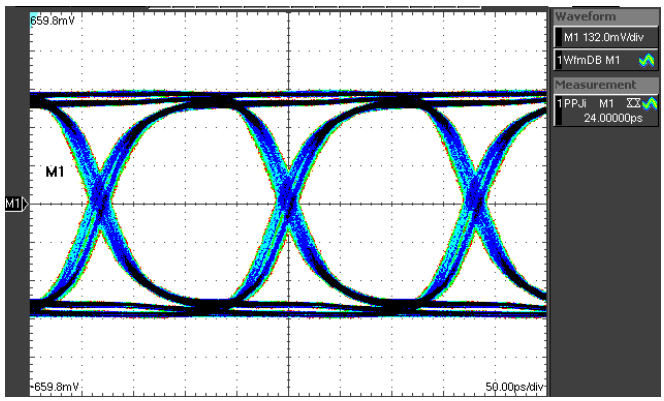

Figure 13. Output Eye Diagram With the TPD2EUSB30/A (Figure 11 Setup, 5 Gbps Data Rate)

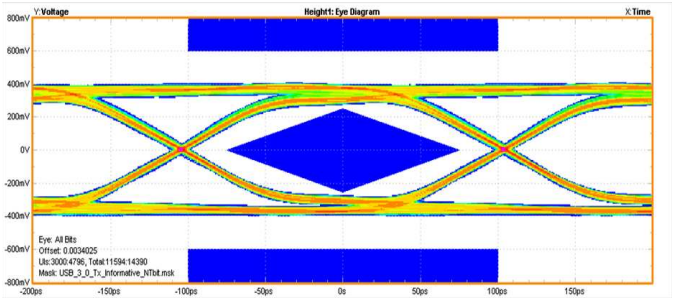

Figure 14. Output Eye Diagram Without the TPD4EUSB30 (5 Gbps Data Rate)

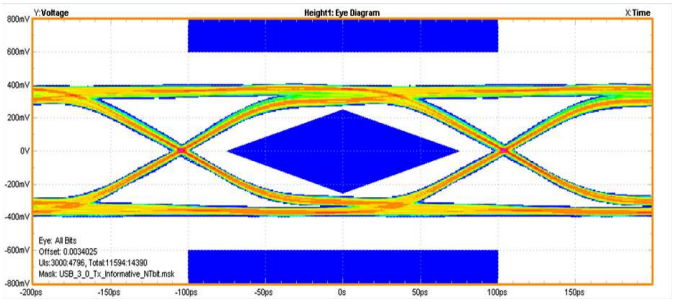

Figure 15. Output Eye Diagram with the TPD4EUSB30 (5 Gbps Data Rate)

9 Power Supply Recommendations

This family of devices are passive ESD protection devices and there is no need to power them. Care should be taken to not violate the maximum voltage specification to ensure that the device functions properly. The D+ and D– lines share a TVS diode which can tolerate up to 6 V.

10 Layout

10.1 Layout Guidelines

- The optimum placement is as close to the connector as possible.
  - EMI during an ESD event can couple from the trace being struck to other nearby unprotected traces, resulting in early system failures.
  - The PCB designer needs to minimize the possibility of EMI coupling by keeping any unprotected traces away from the protected traces which are between the TVS and the connector.
- Route the protected traces as straight as possible.
- Eliminate any sharp corners on the protected traces between the TVS and the connector by using rounded corners with the largest radii possible.
  - Electric fields tend to build up on corners, increasing EMI coupling.

Refer to Figure 16, the TPD2EUSB30/A are offered in space saving DRT package. The DRT is a 1-mm × 1-mm package with flow-through pin-mapping for the high-speed differential lines. The TPD4EUSB30 is offered in space saving DQA package. The DQA is a 1-mm × 2.5-mm package with flow-through pin-mapping for the high-speed differential lines. It is recommended to place the package right next to the USB 3.0 connector. The GND pin should connected to GND plane of the board through a large VIA. If a dedicated GND plane is not present right underneath, it is recommended to route to the GND plane through a wide trace. The current associated with IEC ESD stress can be in the range of 30Amps or higher momentarily. A good, low impedance GND path ensures the system robustness against IEC ESD stress.

The TPDxEUSB30/A can provide system level ESD protection to the high-speed differential ports (> 5 Gbps data rate). The flow-through package offers flexibility for board routing with traces up to 15 mills wide. It allows the differential signal pairs couple together right after they touch the ESD ports of the TPDxEUSB30/A.

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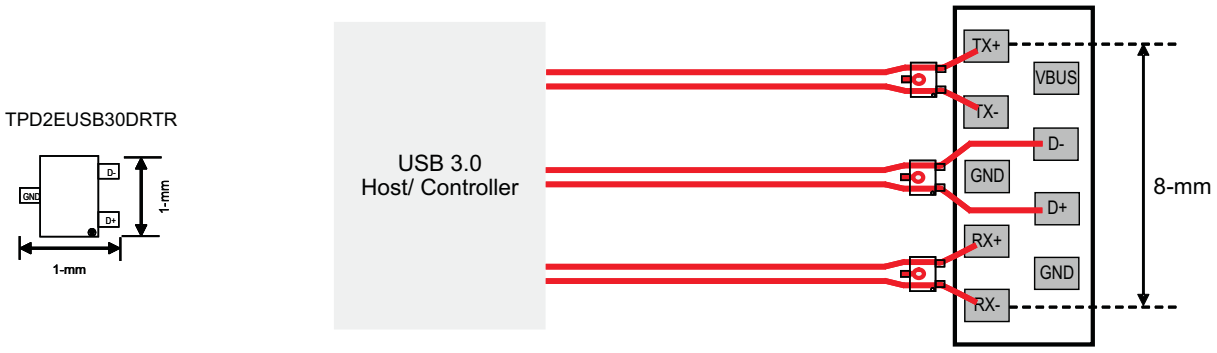
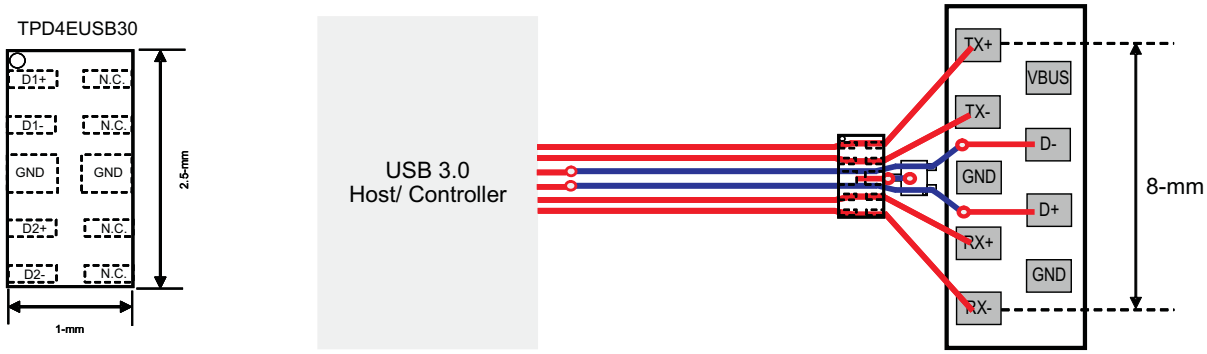
10.2 Layout Examples



Three TPD2EUSB30 to Protect USB3.0 Class A connector (One Layer Routing)



One TPD4EUSB30 & One TPD2EUSB30 to Protect USB3.0 Class A connec tor (Two Layer Routing)

Figure 16. TPDxEUSB30/A at the USB3.0 Class A Connector

Layout Examples (continued)

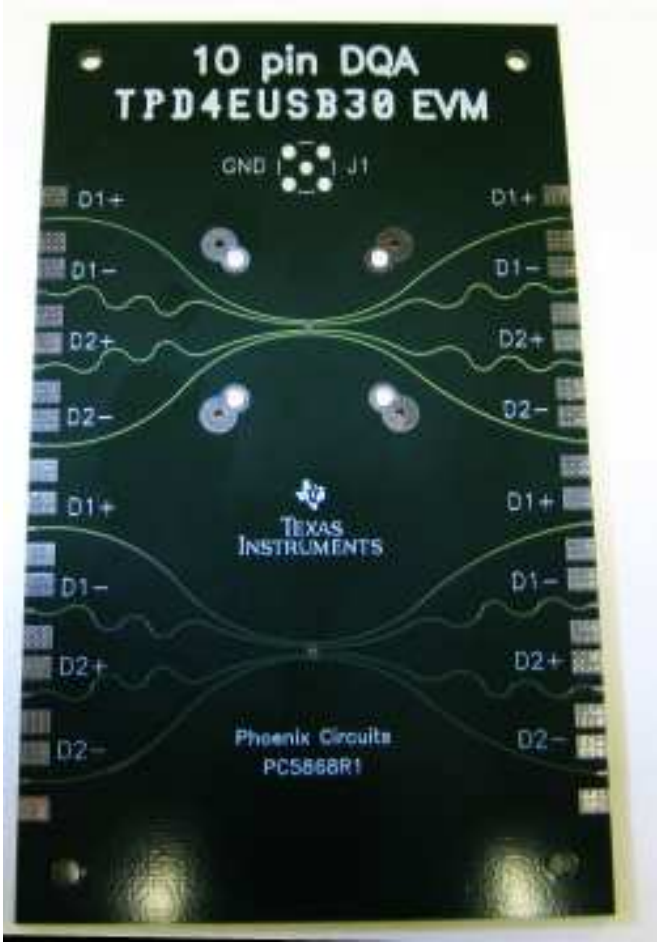


Figure 17. TPDxEUSB30/A EVM – TPD4EUSB30 Side

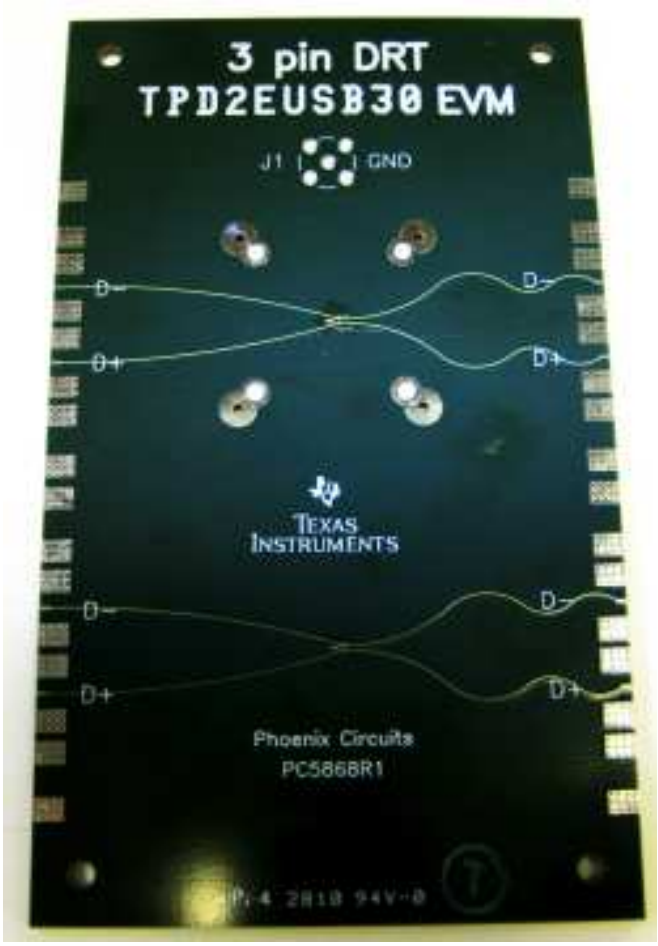


Figure 18. TPDxEUSB30/A EVM – TPD2EUSB30/A Side

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11 Device and Documentation Support

11.1 Related Links

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

Table 2. Related Links

PARTS	PRODUCT FOLDER	SAMPLE & BUY	TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY
TPD2EUSB30	Click here	Click here	Click here	Click here	Click here
TPD2EUSB30A	Click here	Click here	Click here	Click here	Click here
TPD4EUSB30	Click here	Click here	Click here	Click here	Click here

11.2 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community ***TI's Engineer-to-Engineer (E2E) Community.*** Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support ***TI's Design Support*** Quickly find helpful E2E forums along with design support tools and contact information for technical support.

11.3 Trademarks

E2E is a trademark of Texas Instruments.
All other trademarks are the property of their respective owners.

11.4 Electrostatic Discharge Caution

These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

11.5 Glossary

SLYZ022 — *TI Glossary*.

This glossary lists and explains terms, acronyms, and definitions.

12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
TPD2EUSB30ADRTR	ACTIVE	SOT-9X3	DRT	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	5S	Samples
TPD2EUSB30DRTR	ACTIVE	SOT-9X3	DRT	3	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	5P	Samples
TPD4EUSB30DQAR	ACTIVE	USON	DQA	10	3000	Green (RoHS & no Sb/Br)	CU NIPDAU | CU NIPDAUAG	Level-1-260C-UNLIM	-40 to 85	(667 ~ 66O ~ 66R ~ 66V)	Samples

(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".
RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.
Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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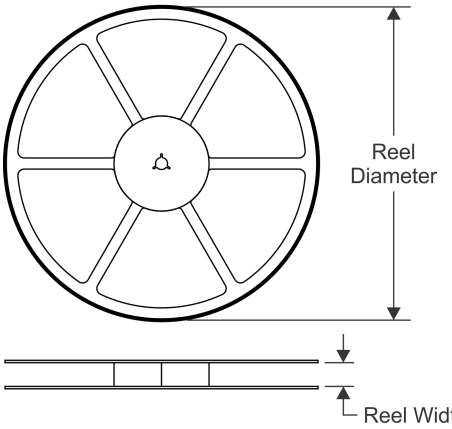
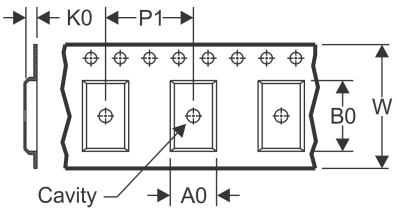
TAPE AND REEL INFORMATION

REEL DIMENSIONS

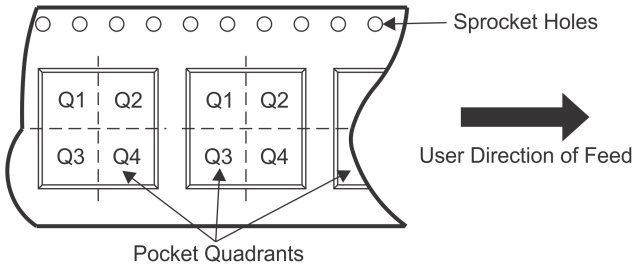


TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

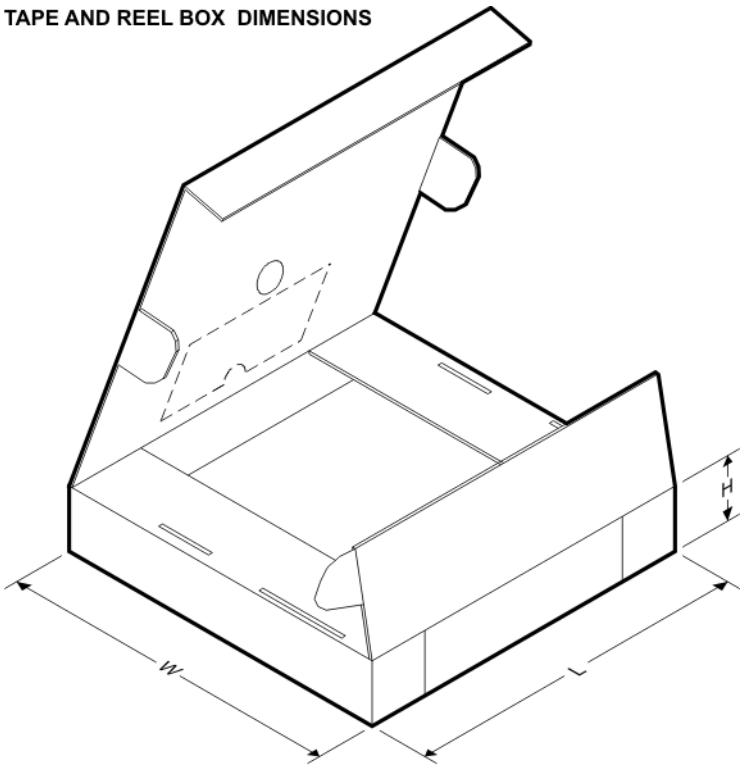
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

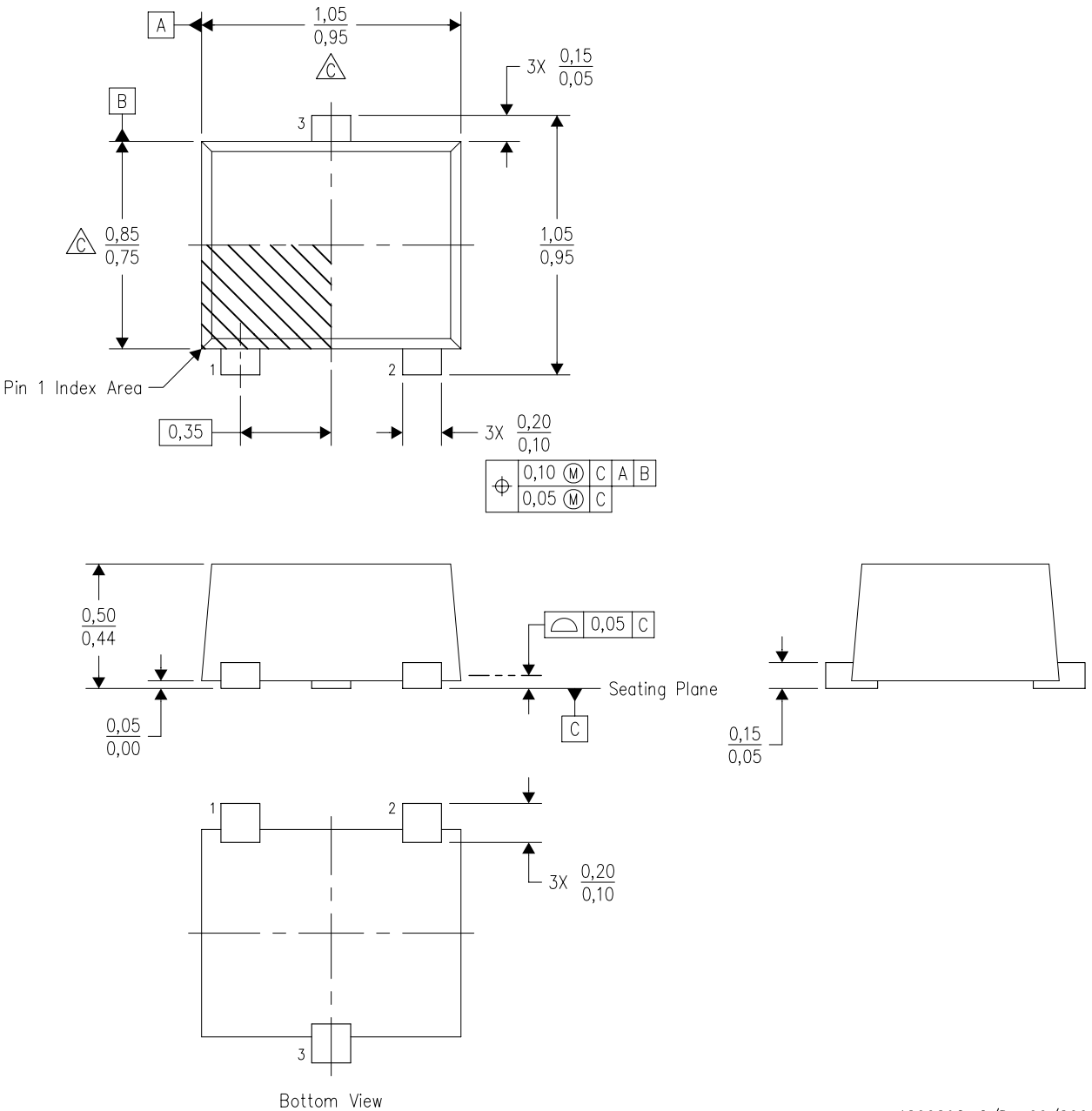
Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TPD2EUSB30ADRTR	SOT-9X3	DRT	3	3000	180.0	8.4	1.16	1.16	0.63	4.0	8.0	Q3
TPD2EUSB30DRTR	SOT-9X3	DRT	3	3000	180.0	8.4	1.16	1.16	0.63	4.0	8.0	Q3
TPD4EUSB30DQAR	USON	DQA	10	3000	180.0	9.5	1.23	2.7	0.7	4.0	8.0	Q1
TPD4EUSB30DQAR	USON	DQA	10	3000	180.0	9.5	1.18	2.68	0.72	4.0	8.0	Q1

TAPE AND REEL BOX DIMENSIONS



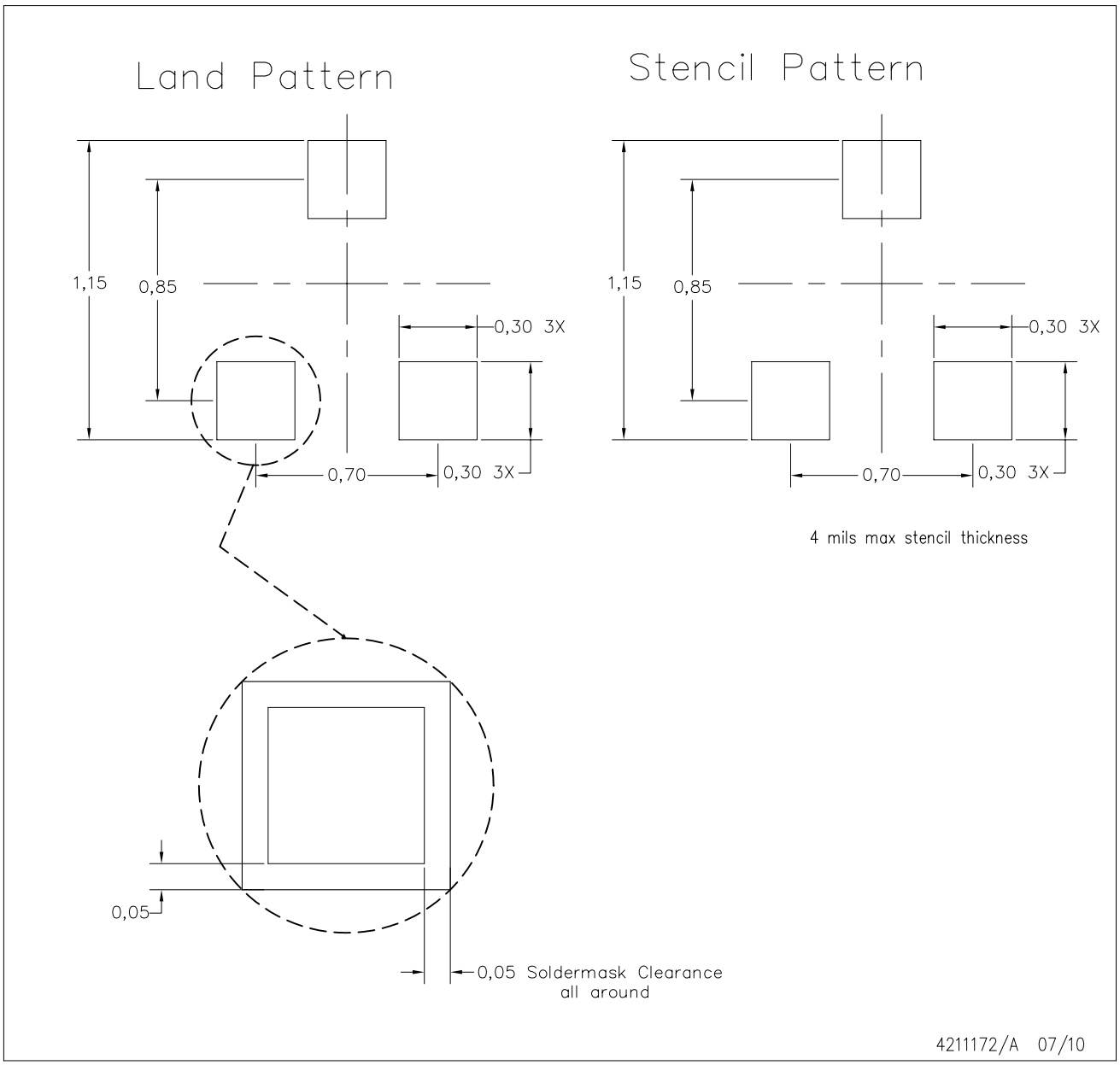
*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TPD2EUSB30ADRTR	SOT-9X3	DRT	3	3000	202.0	201.0	28.0
TPD2EUSB30DRTR	SOT-9X3	DRT	3	3000	202.0	201.0	28.0
TPD4EUSB30DQAR	USON	DQA	10	3000	184.0	184.0	19.0
TPD4EUSB30DQAR	USON	DQA	10	3000	189.0	185.0	36.0



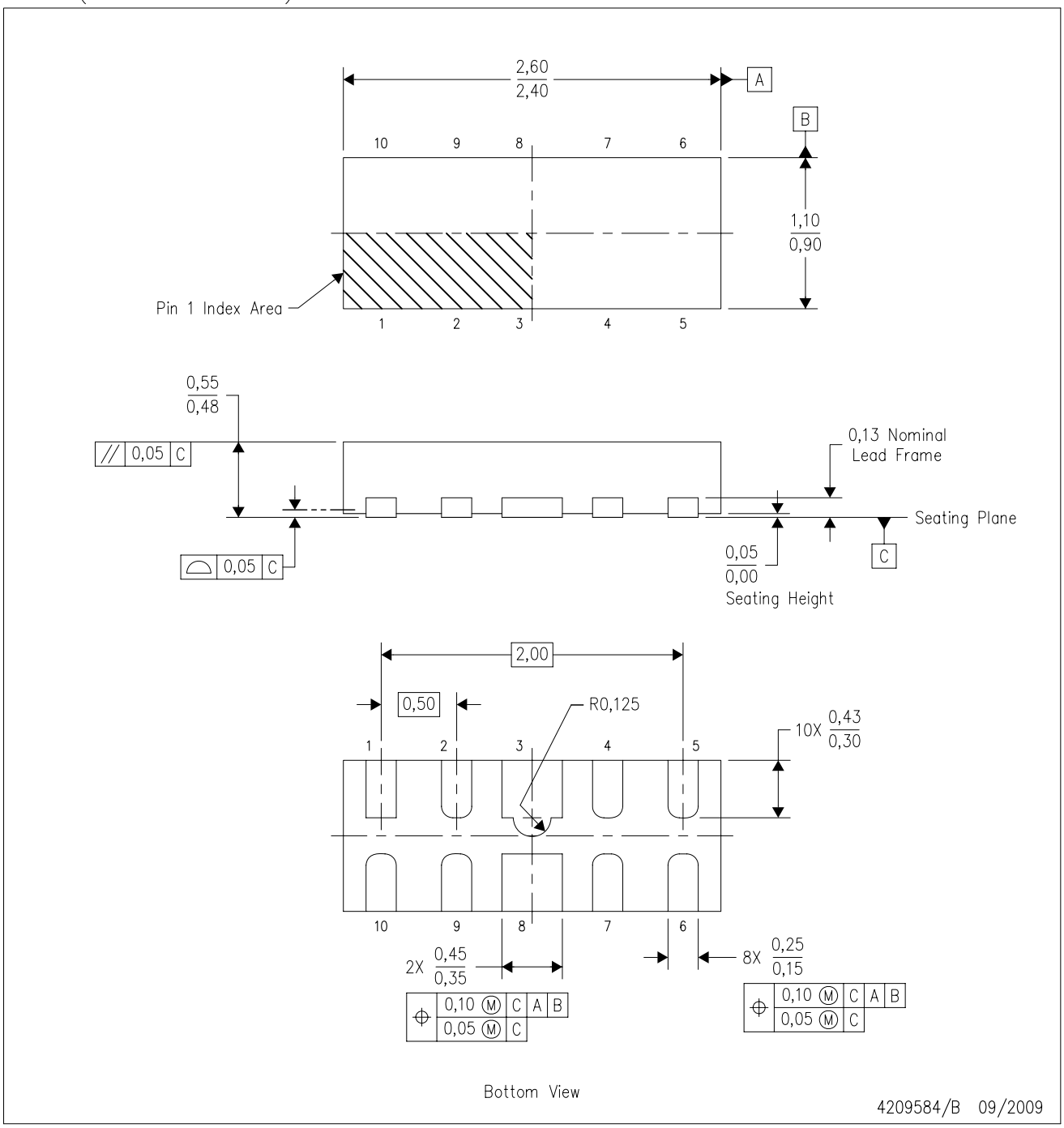
NOTES:
A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M–1994.
B. This drawing is subject to change without notice.
C. Body dimensions do not include mold flash, interlead flash, protrusions, or gate burrs. Mold flash, interlead flash, protrusions, or gate burrs shall not exceed 0,10 per end or side.
D. JEDEC package registration is pending.

DRT (S–PDSO–N3) PLASTIC SMALL OUTLINE



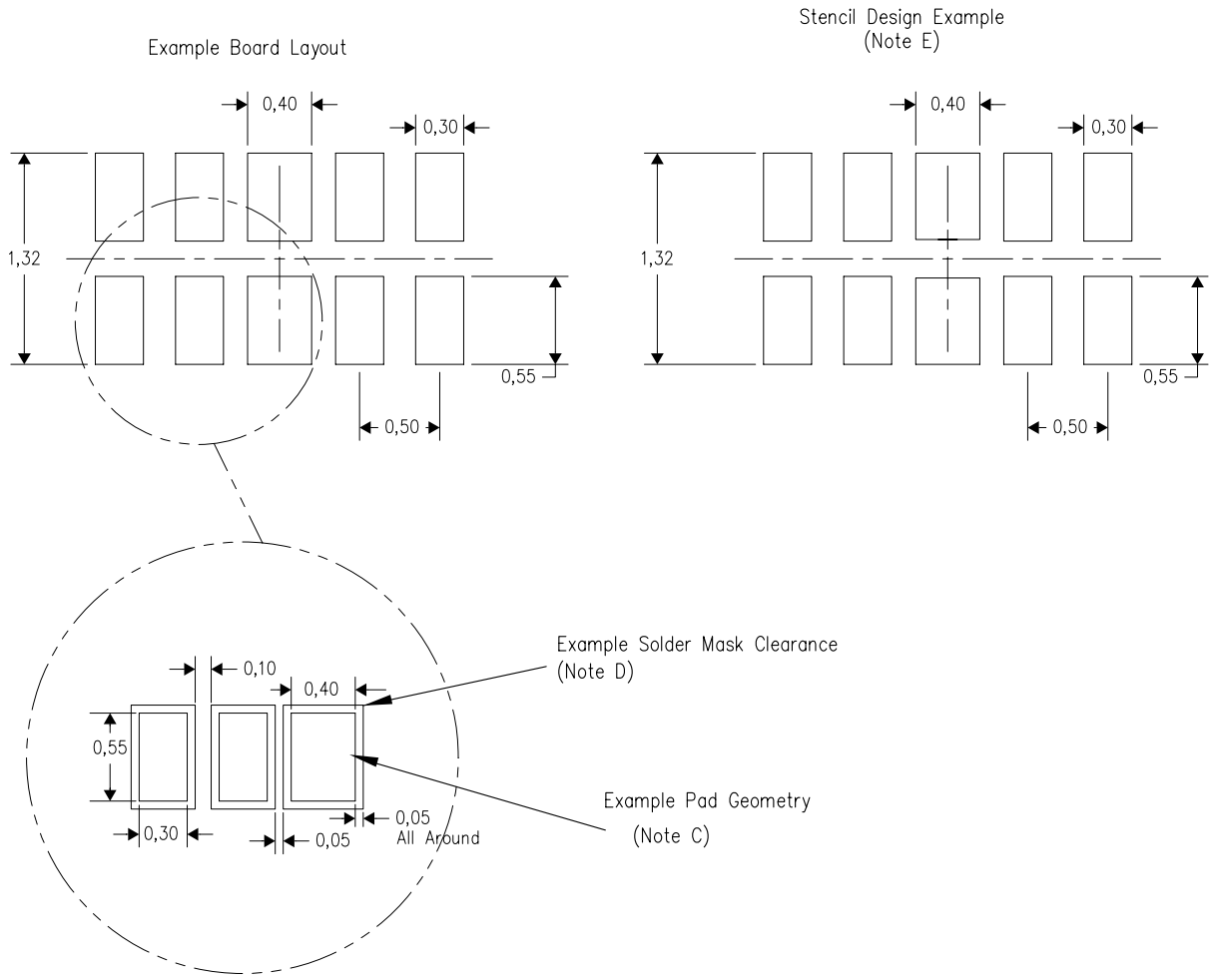
NOTES:
A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Publication IPC–7351 is recommended for alternate designs.
D. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.
E. Maximum stencil thickness 0,1016 mm (4 mils). All linear dimensions are in millimeters.
F. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
G. Side aperture dimensions over–print land for acceptable area ratio > 0.66. Customer may reduce side aperture dimensions if stencil manufacturing process allows for sufficient release at smaller opening.

DQA (R–PSON–N10) PLASTIC SMALL OUTLINE NO–LEAD



NOTES:
A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M–1994.
B. This drawing is subject to change without notice.
C. SON (Small Outline No–Lead) package configuration.

DQA (R–PUSON–N10) PLASTIC SMALL OUTLINE NO–LEAD



NOTES:
A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Publication IPC–7351 is recommended for alternate designs.
D. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.
E. Maximum stencil thickness 0,127 mm (5 mils). All linear dimensions are in millimeters.
F. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
G. Side aperture dimensions over–print land for acceptable area ratio > 0.66. Customer may reduce side aperture dimensions if stencil manufacturing process allows for sufficient release at smaller opening.

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